MRS
BULLETIN

Serving the International
Materials Research Community

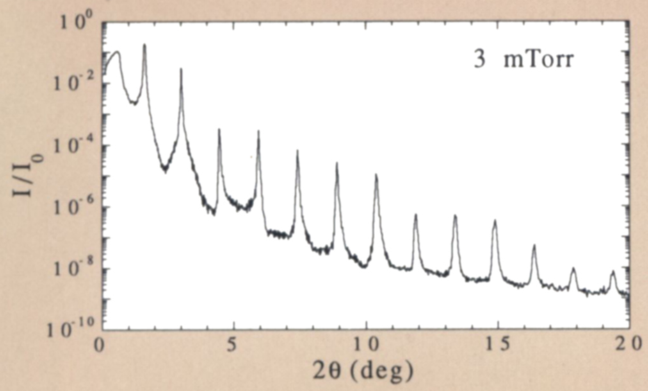
A Publication of the Materials Research Society

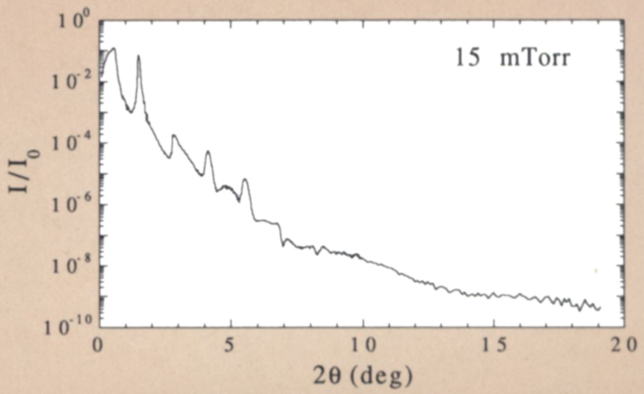
December 1992, Volume XVII, No. 12

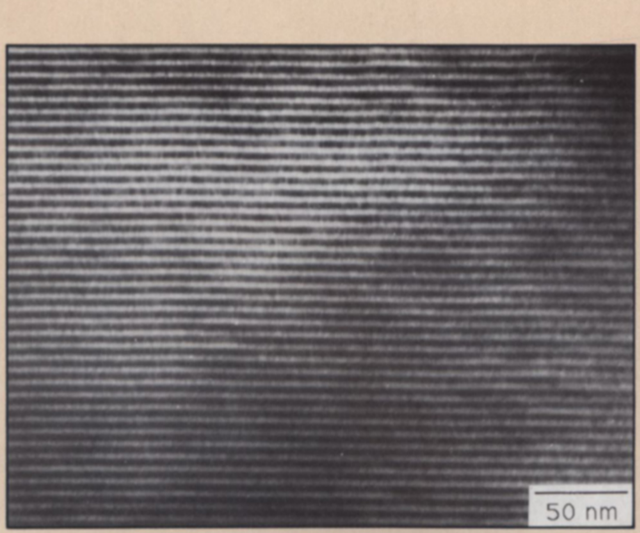
MEMBER OF INTERNATIONAL UNION OF MATERIALS RESEARCH SOCIETIES

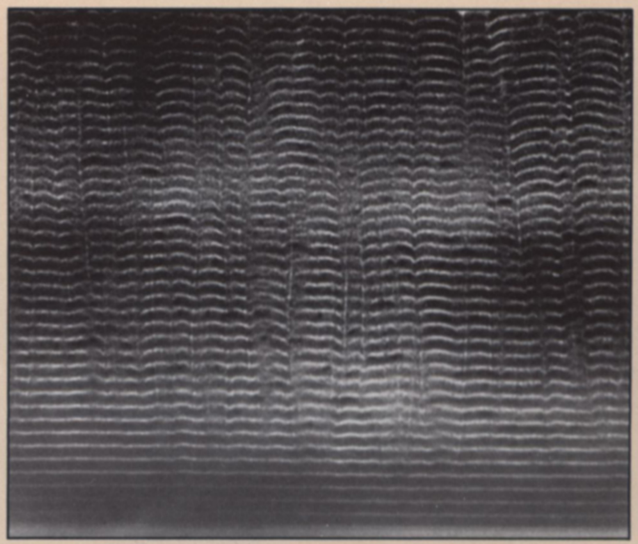
Quantitative Analysis of Thin Films

Part I







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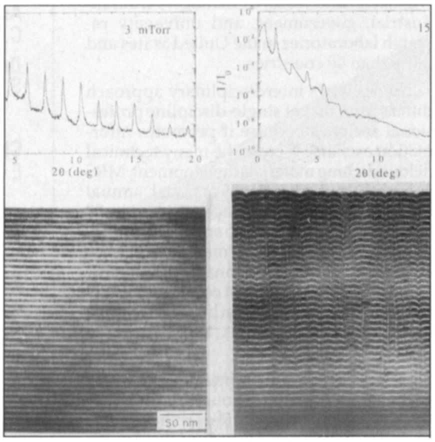
QUANTITATIVE ANALYSIS OF THIN FILMS

MRS NEWS

DEPARTMENTS



ON THE COVER: Low-angle x-ray diffraction spectra and transmission electron microscopy image of $[\mathrm{Nb}(35\ \mathring{A})/\mathrm{Si}(25\ \mathring{A})]_{40}$ superlattices sputtered in an Ar pressure of 3 mTorr (left panels) and 15 mTorr (right panels). For more information on quantitative x-ray diffraction from superlattices, see the article by E.E. Fullerton et al., starting on page 33.

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About the Materials Research Society

The Materials Research Society (MRS), a nonprofit scientific association founded in 1973, promotes interdisciplinary goal-oriented basic research on materials of technological importance. Membership in the Society includes more than 10,000 scientists, engineers, and research managers from industrial, government, and university research laboratories in the United States and more than 40 countries.

The Society's interdisciplinary approach differs from that of single-discipline professional societies because it promotes information exchange across the many technical fields touching materials development. MRS sponsors two major international annual meetings encompassing approximately 50 topical symposia, and also sponsors numerous single-topic scientific meetings. The Society recognizes professional and technical excellence, conducts short courses, and fosters technical interaction in local geographic regions through Sections and University Chapters.

MRS participates in the international arena of materials research through the International Union of Materials Research Societies (IUMRS). MRS is an affiliate of the American Institute of Physics.

MRS publishes symposium proceedings, *MRS Bulletin*, *Journal of Materials Research*, and other publications related to current research activities.

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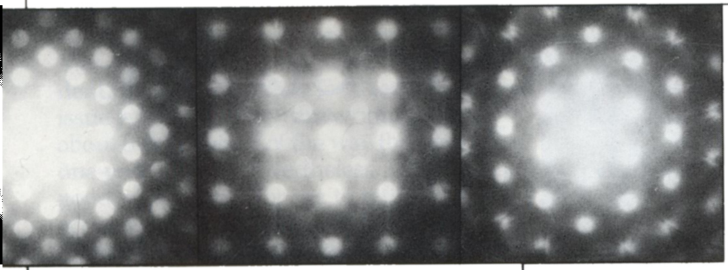
THE BEST WAY TO GET AN ANGLE ON CRYSTALS.



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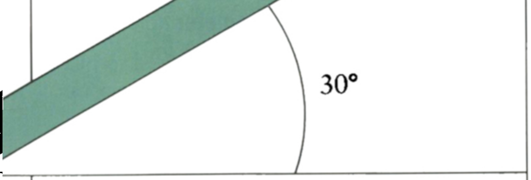

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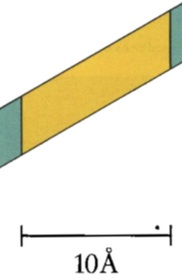

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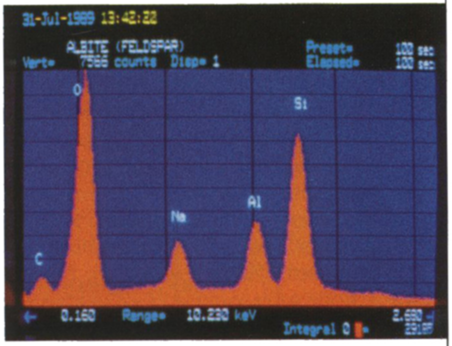

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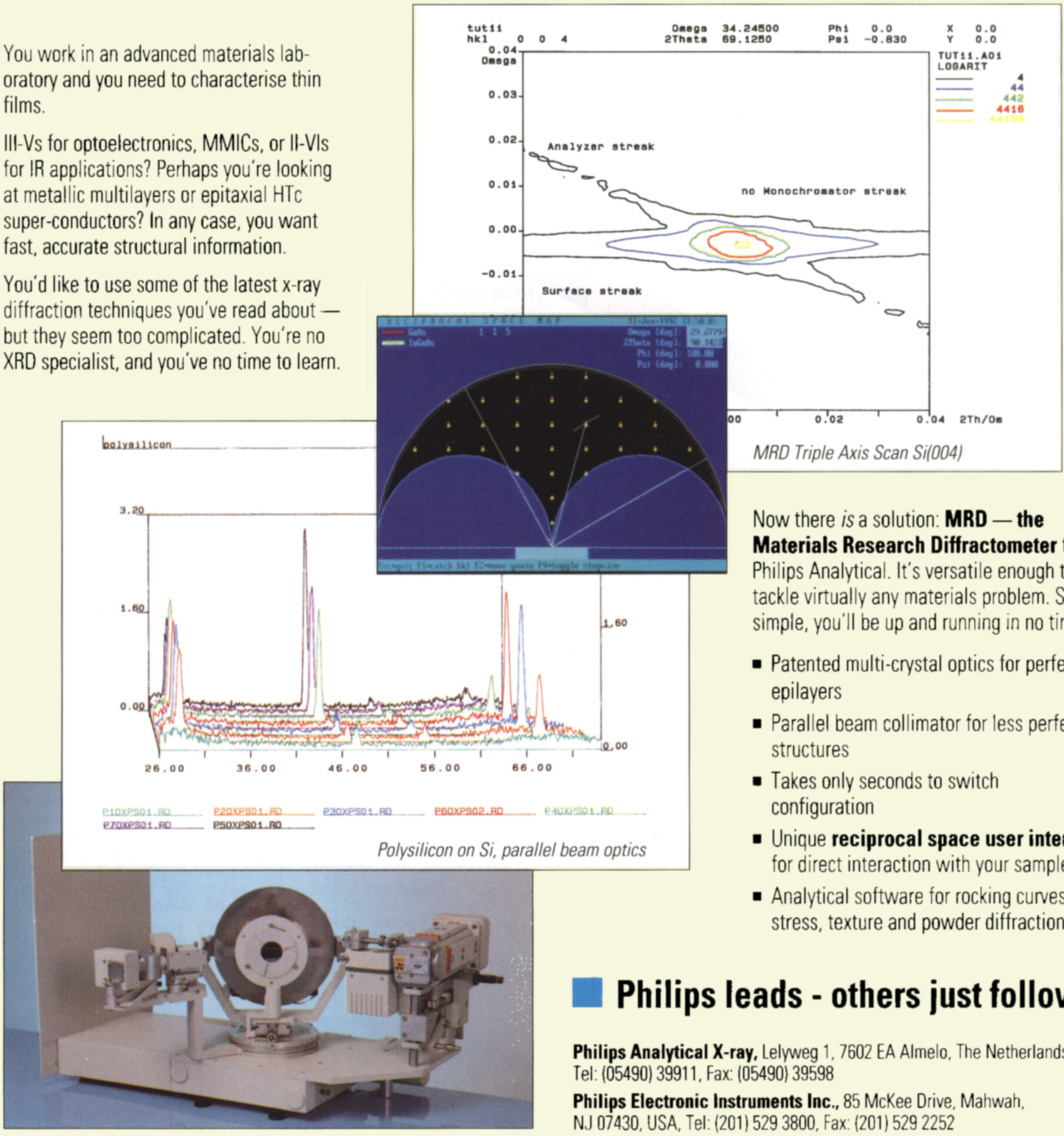

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